

PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

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	PPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	13	EXAMINER		
1	0039852	10/22/2001	714	738	2133	4/2	227		
**A	PPLICANT	S: Shih Ko	-Yan; Hs	u Ming-Hsun;					
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	35 USC 119 conditions met ☐ yes ☐ no Verified and Acknowledged Examiners's initials						2		
TITL	TITLE : Method and circuit for testing a chip								
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NOTICE OF ALL	OWANCE MAILED		CLAIMS ALLOWED					
		Assistant Examiner	Total Claims		Print Claim for O.G			
ISS	SUE FEE		DRAWING					
Amount Due	Date Paid	7	Sheets Drwg.	Figs.Drwg.	Print Fig.			
·	<u> </u>	Primary Examiner	Application Examiner					
TE	RMINAL	PREPARED FOR ISSUE						
	DISCLAMER	WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.						

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